

9/13/2011

PRODUCT RELIABILITY REPORT FOR

MAX34406

Maxim Integrated Products

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Prepared by:

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Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

MAX34406

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at http://www.maxim-ic.com/TechSupport /dsreliability.html.

Device Description:

A description of this device can be found in the product data sheet. You can find the product data sheet at http://dbserv.maxim-ic.com/l_datasheet3.cfm.

Reliability Derating:

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

AfT = exp((Ea/k)*(1/Tu - 1/Ts)) = tu/ts AfT = Acceleration factor due to Temperature tu = Time at use temperature (e.g. 55°C) ts = Time at stress temperature (e.g. 125°C) k = Boltzmann's Constant (8.617 x 10-5 eV/°K) Tu = Temperature at Use (°K) Ts = Temperature at Stress (°K) Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

AfV = exp(B*(Vs - Vu)) AfV = Acceleration factor due to Voltage Vs = Stress Voltage (e.g. 7.0 volts) Vu = Maximum Operating Voltage (e.g. 5.5 volts) B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

Fr = X/(ts * AfV * AfT * N * 2)X = Chi-Sq statistical upper limit N = Life test sample size Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

MTTF = 1/Fr

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

	FAILURE RATE	E: M	TTF (YRS):	83132		FITS:	1.4			
		DEVIC	CE HOURS:	667271870	F	AILS:	0			
Only data from Operating Life or similar stresses are used for this calculation.										
The parameters used to calculate this failure rate are as follows:										
	Cf: 60%	Ea: 0.7	B: 0	Tu:	25	°C	Vu: 5	Volts		

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

Device Information:											
Process:	B8, Sa	B8, San Antonio B8 flow with TMA Topglass.									
Passivation:	OxyNit	OxyNit LaserNoA&E - Pass/Nov.TEOS/OxyNit -Gen.LaserP									
Die Size:		85 x 90	85 x 90								
Number of Trans	587	587									
Interconnect:			Aluminum / 0.5% Copper								
Gate Oxide Thickness:		NA	NA								
ESD HBM											
DESCRIPTION	DATE	CODE/PRODU	JCT/LOT	CONDITION	RE	DPOIN	QTY	FAILS	FA#		
ESD SENSITIVITY	1118	MAX34406	ZJ168552AC	JESD22-A114 HBM 500 VOLTS	1	PUL'S	5	0			
ESD SENSITIVITY	1118	MAX34406	ZJ168552AC	JESD22-A114 HBM 1000 VOLTS	1	PUL'S	5	0			
ESD SENSITIVITY	1118	MAX34406	ZJ168552AC	JESD22-A114 HBM 1500 VOLTS	1	PUL'S	5	0			
ESD SENSITIVITY	1118	MAX34406	ZJ168552AC	JESD22-A114 HBM 2000 VOLTS	1	PUL'S	5	0			
ESD SENSITIVITY	1118	MAX34406	ZJ168552AC	JESD22-A114 HBM 2500 VOLTS	1	PUL'S	5	0			
					Total:			0			
LATCH-UP											
DESCRIPTION	DATE	CODE/PRODU	JCT/LOT	CONDITION	RE	ADPOIN	QTY	FAILS	FA#		
LATCH-UP I	1118	MAX34406	ZJ168552AC	JESD78A, I-TEST 25C 100mA			6	0			
LATCH-UP V	1118	MAX34406	ZJ168552AC	JESD78A, V-SUPPLY TEST 25C			6	0			
					Tota	d:		0			
OPERATING LIFE											
DESCRIPTION	DATE	CODE/PRODU	JCT/LOT	CONDITION	RE	DPOIN	QTY	FAILS	FA#		

HIGH TEMP OP LIFE	0724	DS8007	QN616349B	125C,	6.0 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0740	DS8007	QN824614B	125C,	6.0 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	0740	DS8007	XN716349CA	125C,	6.0 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	0744	DS8113	QK732036AB	125C,	6.0 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0750	DS8007	QN824614A	125C,	6.0 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	0821	DS2413	WJ840032AB	125C,	5.25 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0833	DS8024	QM832036G	125C,	6.0 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0834	DS8023	QM840693B	125C,	6.0 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0837	DS2413	WJ942402BE	125C,	5.25 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0839	DS8007	SN839727AA	125C,	6.0 VOLTS	192	HRS	120	0
HIGH TEMP OP LIFE	0851	DS8313	QM941961B	125C,	6.0 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0940	DS8113	FM948234AA	125C,	6.0 VOLTS	1000	HRS	80	0
HIGH TEMP OP LIFE	0944	DS2413	QJ094300AB	125C,	5.25 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	1118	MAX34406		125C, (PSD)	5.0V (PSA) & 20.0V	192	HRS	70	0
						Total:			0
FAILURE RATE:		MTTF (YRS)	: 831	32	FITS:	1.4			
	D	EVICE HOURS	: 6672718	370	FAILS:	0			